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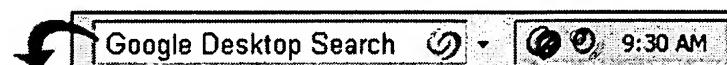
Gate direct tunneling. • Impact of halos on output resistance. • **Well Proximity**

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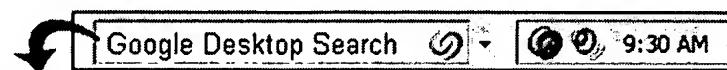
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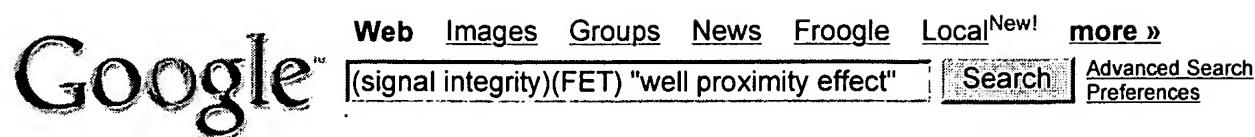
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1. **Very low threshold oxide-confined 1.3 μm GaAs-based quantum dot lasers**
Park, G.; Shchekin, O.B.; Huffaker, D.L.; Deppe, D.G.;
Lasers and Electro-Optics, 2000. (CLEO 2000). Conference on
7-12 May 2000 Page(s):349 - 350
Digital Object Identifier 10.1109/CLEO.2000.907100
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2. **Reduced threshold vertical-cavity surface-emitting lasers**
Young, D.B.; Kapila, A.; Scott, J.W.; Malhotra, V.; Coldren, L.A.;
Electronics Letters
Volume 30, Issue 3, 3 Feb. 1994 Page(s):233 - 235
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3. **Multi-quantum well GaInNAs/GaAs lasers with low threshold current density by MOCVD**
Cheng, J.; Li, N.Y.; Hains, C.P.; Yang, K.;
Device Research Conference Digest, 1999 57th Annual
28-30 June 1999 Page(s):192 - 193
Digital Object Identifier 10.1109/DRC.1999.806368
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Polishchuk, I.; Mathur, N.; Sandstrom, C.; Manos, P.; Pohland, O.; Semiconductor Manufacturing, 2005. ISSM 2005, IEEE International Symposium 13-15 Sept. 2005 Page(s):193 - 196
Digital Object Identifier 10.1109/ISSM.2005.1513333

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